

INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Industrial-process measurement and control – Data structures and elements in process equipment catalogues –
Part 41: Lists of properties (LOPs) of process analysers for electronic data exchange – Generic structures**

Mesure et commande dans les processus industriels – Éléments et structures de données dans les catalogues d'équipements de processus –

Partie 41: Listes des propriétés (LOP) des analyseurs de processus pour l'échange électronique de données – Structures génériques



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INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

COMMISSION
ELECTROTECHNIQUE
INTERNATIONALE

ICS 01.140.30

ISBN 978-2-8327-0369-4

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**INDUSTRIAL-PROCESS MEASUREMENT AND CONTROL –
DATA STRUCTURES AND ELEMENTS IN PROCESS
EQUIPMENT CATALOGUES –****Part 41: Lists of properties (LOPs) of process analysers
for electronic data exchange – Generic structures**

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The text of this International Standard is based on the following documents:

Draft	Report on voting
65E/1067/CDV	65E/1091/RVC

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

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